

Docket No.: 060188-0782



PATENT

IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of : Customer Number: 53080
Toyoji ITO : Confirmation Number: 3918
Application No.: 10/786,070 : Group Art Unit: 2823
Filed: February 26, 2004 : Examiner: PARKER, John M.
For: METHOD FOR FABRICATION SEMICONDUCTOR DEVICE

INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed more than three months after the U.S. filing date AND after the mailing date of the first Office Action on the merits, but before the mailing date of a Final Rejection or Notice of Allowance.

CERTIFICATION PARAGRAPH

The undersigned certifies that each item of information contained in this Information Disclosure Statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement as described in 37 CFR 1.97(e)(1).

Each reference was first cited in a corresponding foreign application office action and its relevance discussed therein. Please note that the third reference cited by the office action, JP 61-296722, was previously submitted to the Patent and Trademark Office on February 26, 2004. A copy of the foreign office action, together with an English language version thereof, is attached for the Examiner's information.

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

McDERMOTT WILL & EMERY LLP

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INFORMATION DISCLOSURE CITATION IN ANOTHER APPLICATION  (PTO-1449)			ATTY. DOCKET NO. 060188-0782	SERIAL NO. 10/786,070		
			APPLICANT Toyoji ITO			
			FILING DATE February 26, 2004	GROUP 2823		
U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ₂ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document		
		US				
		US				
		US				
		US				
FOREIGN PATENT DOCUMENTS						
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number -Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation Yes No
		JP 05-090420	04/09/1993	SONY CORP		JAPAN (w/ English Abstract)
		JP 01-287948	11/20/1989	FUJI XEROX CO LTD		JAPAN (w/ English Abstract)
		JP 01-268042	10/25/1989	HITACHI LTD		JAPAN (w/ English Abstract)
		JP 63-122125	05/26/1988	SEIKO EPSON CORP		JAPAN (w/ English Abstract)
		JP 08-139293	05/31/1996	TOSHIBA CORP		JAPAN (w/ English Abstract)
		JP 2000-124427	04/28/2000	SIEMENS AG		JAPAN (w/ English Abstract)
		JP 2002-231905	08/16/2002	MATSUSHITA ELECTRIC IND CO LTD		JAPAN (w/ English Abstract)
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)						
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				
EXAMINER			DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.